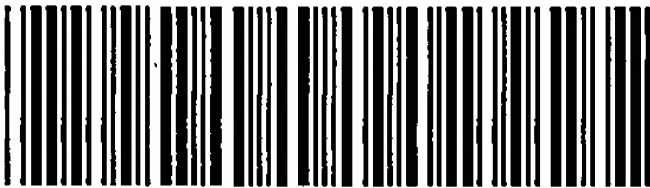


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/669,210	YAMAGUCHI ET AL.	
	Examiner	Art Unit	
	Anish Sikri	2109	

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Class	Subclass	Date	Examiner
709	227	5/11/2007	AS

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East Image and Keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO and IBM_TDB (see attached search strategy)	5/11/2007	AS
Inventor name and Assignee search in PALM ExPO and EAST	5/11/2007	AS
Consulted with Rafael Perez-Gutierrez and George Bugg	5/11/2007	AS
"6973671".pn. "20020023143".did. "20030115142".did.	5/11/2007	AS
S8 and (((service or content or data) adj2 server) same (service adj2 list))	5/11/2007	AS